

STL100N3LLH6

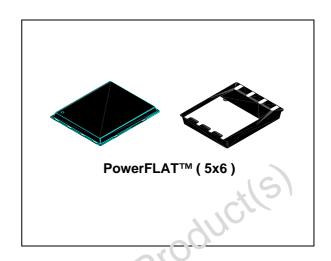
N-channel 30 V, 0.0025 Ω, 25 A PowerFLAT™ (5x6) STripFET™ VI DeepGATE™ Power MOSFET

Preliminary data

Features

Туре	Type V _{DSS}		I _D	
STL100N3LLH6	30 V	$0.0035~\Omega$	25 A ⁽¹⁾	

- 1. The value is rated according $R_{\mbox{\scriptsize thj-pcb}}$
- R_{DS(on)} * Q_g industry benchmark
- Extremely low on-resistance R_{DS(on)}
- High avalanche ruggedness
- Low gate drive power losses
- Very low switching gate charge



Application

■ Switching applications

Description

This product utilizes the 6th generation of design rules of ST's proprietary STripFETTM technology, with a new gate structure. The resulting Power MOSFET exhibits the lowest $R_{DS(on)}$ in a.! packages.

Figure 1. Internal schematic diagram

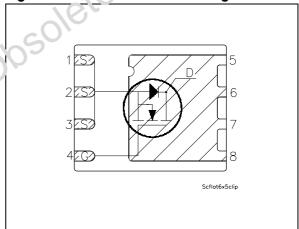


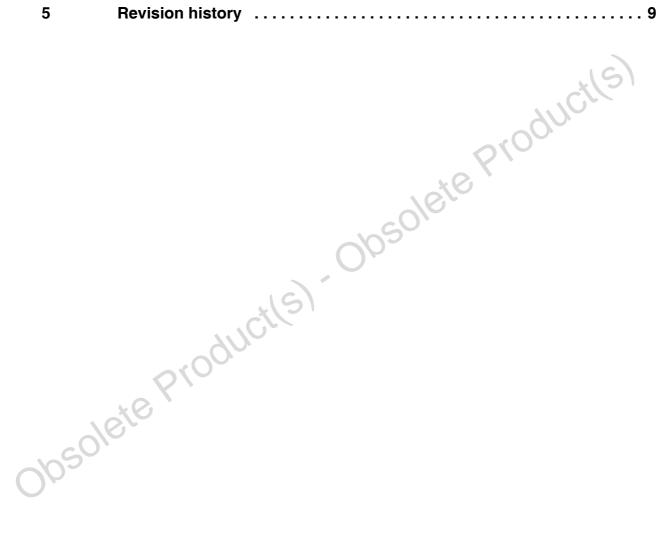
Table Device summary

10	Order code	Marking	Package	Packaging
	STL100N3LLH6	100N3LLH6	PowerFLAT™ (5x6)	Tape and reel

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STL100N3LLH6 **Electrical ratings**

Electrical ratings 1

Table 2. **Absolute maximum ratings**

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage (V _{GS} = 0)	30	V
V _{GS}	Gate-source voltage	± 20	V
I _D ⁽¹⁾	Drain current (continuous) at T _C = 25 °C	100	Α
I _D ⁽¹⁾	Drain current (continuous) at T _C = 100 °C	62.5	Α
I _D ⁽²⁾	Drain current (continuous) at T _C = 25 °C	25	Α
I _D ⁽²⁾	Drain current (continuous) at T _C =100 °C	16	Α
I _{DM} ⁽³⁾	Drain current (pulsed)	100	Α
P _{TOT} ⁽¹⁾	Total dissipation at T _C = 25 °C	60	W
P _{TOT} (2)	Total dissipation at T _C = 25 °C	4	W
	Derating factor	0.03	W/°C
T _J T _{stg}	Operating junction temperature Storage temperature	-55 to 150	°C

^{1.} The value is rated according $R_{\mbox{\scriptsize thj-c}}$

Table 3. Thermal resistance

' stg	5 1						
1. The value i	1. The value is rated according R _{thi-c}						
2. The value i	s rated according R _{thj-pcb}						
Pulse width	Pulse width limited by safe operating area						
Table 3. Thermal resistance							
Table 3.	Thermal resistance						
Table 3.	Thermal resistance Parameter	Value	Unit				
		Value 2.08	Unit °C/W				

^{1.} When mounted on FR-4 board of 1inch², 2oz Cu, t < 10 sec

Table 4. Avalanche data

Symbol	Parameter	Value	Unit
I _{AV}	Not-repetitive avalanche current, (pulse width limited by Tj Max)	TBD	Α
E _{AS}	Single pulse avalanche energy (starting $T_J = 25$ °C, $I_D = I_{AV}$, $V_{DD} = 24$ V)	TBD	mJ

^{2.} The value is rated according $R_{\mbox{\scriptsize thj-pcb}}$

^{3.} Pulse width limited by safe operating area

Electrical characteristics STL100N3LLH6

2 **Electrical characteristics**

(T_{CASE} = 25 °C unless otherwise specified)

On/off states Table 5.

Symbol	mbol Parameter Test conditions M		Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_D = 250 \mu A, V_{GS} = 0$	30	-	-	٧
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = Max rating, V _{DS} = Max rating @125 °C	-	-	1 10	μA μA
I _{GSS}	Gate body leakage current (V _{DS} = 0)	V _{GS} = ±20 V	-	-	±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1	-	-	V
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10 V, I _D = 12.5 A V _{GS} = 4.5 V, I _D = 12.5 A	-	0.0025 0.0042	0.0035 0.005	Ω Ω
Table 6.	Dynamic		(910	Cr	
Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit

Table 6. **Dynamic**

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 25 \text{ V, f=1 MHz,}$ $V_{GS} = 0$	-	3500 650 450	-	pF pF pF
Qg	Total gate charge	$V_{DD} = 15 \text{ V}, I_D = 25 \text{ A}$		39		nC
Q_gs	Gate-source charge	V _{GS} =4.5 V	-	TBD	-	nC
Q_{gd}	Gate-drain charge	(see Figure 3)		TBD		nC
R _G	Gate input resistance	f=1 MHz Gate DC Bias = 0 Test signal level = 20 mV open drain	-	TBD	-	Ω

		20/0	open drain				
	0	40					
	Table 7.	Switching times					
	Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Opso	t _{d(on)} t _r t _{d(off)}	Turn-on delay time Rise time Turn-off delay time	V_{DD} =15 V, I_{D} = 12.5 A, R_{G} =4.7 Ω , V_{GS} =10 V (see Figure 2)	-	TBD TBD TBD	-	ns ns ns
	t _f	Fall time	(366 Figure 2)		TBD		ns

Table 8. Source drain diode

Symbol	Parameter	Test conditions	Min	Тур.	Max	Unit
I _{SD}	Source-drain current		-	-	25	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)		-	-	100	Α
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 25 A, V _{GS} =0	-	-	1.1	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 12.5 \text{ A},$ di/dt = 100 A/ μ s, $V_{DD} = 25 \text{ V}$	-	TBD TBD TBD	-	ns nC A

^{1.} Pulse width limited by safe operating area

Obsolete Product(s). Obsolete Product(s)

^{2.} Pulsed: pulse duration=300µs, duty cycle 1.5%

Test circuits STL100N3LLH6

3 Test circuits

Figure 2. Switching times test circuit for resistive load

Figure 3. Gate charge test circuit

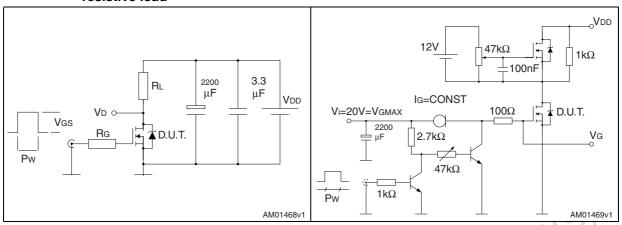


Figure 4. Test circuit for inductive load switching and diode recovery times

Figure 5. Unclamped inductive load test circuit

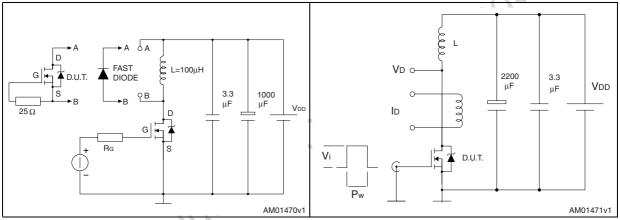
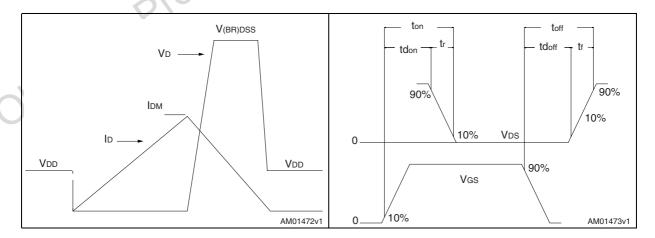


Figure 6. Unclamped inductive waveform

Figure 7. Switching time waveform



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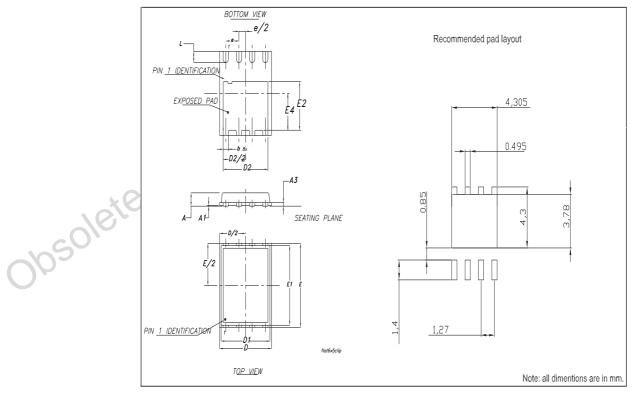
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

Obsolete Product(s). Obsolete Product(s)

PowerFLAT™ (5x6) mechanical data

DIM.		mm.			inch	
DIN.	Min.	Тур.	Max.	Min.	Тур.	Max.
А	0.80	0.83	0.93	0.031	0.32	0.036
A1		0.02	0.05		0.0007	0.0019
A3		0.20			0.007	
b	0.35	0.40	0.47	0.013	0.015	0.018
D		5.00			0.196	
D1		4.75			0.187	
D2	4.15	4.20	4.25	0.163	0.165	0.167
Е		6.00			0.236	
E1		5.75			0.226	
E2	3.43	3.48	3.53	0.135	0.137	0.139
E4	2.58	2.63	2.68		0.103	0.105
е		1.27			0.050	
L	0.70	0.80	0.90	0.027	0.031	0.035



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STL100N3LLH6 Revision history

5 Revision history

Table 9. Document revision history

Date	Revision	Changes
09-Apr-2009	1	First release.
26-Jan-2010	2	Document status promoted from target specification to preliminary data.
16-Feb-2010	3	Test condition in <i>Table 7</i> has been changed.



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